



RADIO TEST REPORT

Test Report No. : 28IE0011-HO-01-A-R1

Applicant : Sony Corporation
Type of Equipment : Digital Photo Frame
Model No. : VGF-CP1
FCC ID : AK8VGFCP1
Test regulation : FCC Part 15 Subpart C 2008
Section 15.207, Section 15.247
Test Result : Complied

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2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.
6. Original test report number of this report is 28IE0011-HO-01-A.

Date of test: April 14 to 19, 2008

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SECTION 1: Customer information

Company Name : Sony Corporation
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Contact Person : Michio Kobayashi

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Digital Photo Frame
Model No. : VGF-CP1
Serial No. : 1000009
Rating : DC6.0V
Receipt Date of Sample : April 7, 2008
Country of Mass-production : Japan
Condition of EUT : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab

2.2 Product Description

Model No: VGF-CP1 (referred to as the EUT in this report) is the Digital Photo Frame.
Feature of EUT: Digital photo frame and share the photo via internet with WLAN.
EUT clock: CPU133MHz

Transmitter part

Frequency of Operation : 2412 - 2462MHz
Bandwidth & Channel Spacing : 22MHz & 5MHz
Modulation : DSSS, OFDM
Other clock Frequency : 26MHz, 24MHz
Operating voltage(inner) : DC 1.8 / 3.3V
Antenna Type : Inverted F Antenna
Antenna Connector Type : U.FL-LP-066
Antenna Gain : +0.22dBi
Method of Frequency Generation : Crystal

Receiver part

Other Clock Frequency : 40MHz
Operating voltage(inner) : DC 1.8 / 3.3V
Antenna Type : Inverted F Antenna
Antenna connector Type : U.FL-LP-066
Method of Frequency Generation : Crystal

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SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part15 Subpart C: 2008, final revised on March 24, 2008

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators
Section 15.207 Conducted limits
Section 15.247 Operation within the bands 902-928MHz,
2400-2483.5MHz, and 5725-5850MHz

FCC 15.31 (e)

This EUT provides stable voltage(DC1.8 / 3.3V) constantly to RF Module regardless of input voltage. Therefore, this EUT complies with the requirement.

FCC Part 15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

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3.2 Procedures and results

No.	Item	Test Procedure	Specification	Remarks	Deviation	Worst margin	Results
1	Conducted emission	FCC: ANSI C63.4:2003 7. AC powerline conducted emission measurements IC: RSS-Gen 7.2.2	FCC: Section 15.207 IC: RSS-Gen 7.2.2	Conducted	N/A	QP 15.4dB 0.18552MHz, L AV 17.6dB 0.18712MHz, N	Complied
2	6dB Bandwidth	FCC: "Guidance on Measurement of Digital Transmission Systems Operating under Section15.247" IC: RSS-Gen 4.6.2	FCC: Section 15.247(a)(2) IC: RSS-210 A8.2(a)	Conducted	N/A	See data.	Complied
3	Maximum Peak Output Power	FCC: "Guidance on Measurement of Digital Transmission Systems Operating under Section15.247" IC: RSS-Gen 4.8	FCC: Section 15.247(b)(3) IC: RSS-210 A8.4(4)	Conducted	N/A		Complied
4	Restricted Band Edges	FCC: "Guidance on Measurement of Digital Transmission Systems Operating under Section15.247" IC: -	FCC: Section 15.247 (d) IC: RSS-210 A8.5	Conducted/ Radiated	N/A		Complied
5	Power Density	FCC: "Guidance on Measurement of Digital Transmission Systems Operating under Section15.247" IC: -	FCC: Section 15.247 (e) IC: RSS-210 A8.2(b)	Conducted	N/A		Complied
6	Spurious Emission	FCC: "Guidance on Measurement of Digital Transmission Systems Operating under Section15.247" IC: RSS-Gen 4.9 RSS-Gen 4.10	FCC: Section15.247(d) IC: RSS-210 A8.5 RSS-Gen 7.2.1 and 7.2.3	Conducted/ Radiated	N/A		[Tx] 5.5dB 157.448MHz, Vertical, QP [Rx] 6.7dB 959.994MHz Horizontal, QP

Note: UL Japan, Inc.'s EMI Work Procedures No.QPM05 and QPM15.

*These tests were performed without any deviations from test procedure except for additions or exclusions.

* In case any questions arise about test procedure, ANSI C63.4: 2003 is also referred.

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3.3 Addition to standards

No.	Item	Test Procedure	Specification	Remarks	Deviation	Worst margin	Results
1	99% Occupied Band Width	IC: RSS-Gen 4.6.1	IC: RSS-Gen 4.6.1	Conducted	N/A	N/A	N/A

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room	Conducted emission	Radiated emission (10m*)			Radiated emission (3m*)			Radiated emission (3m*)	
	150kHz-30MHz	9kHz-30MHz	30MHz-300MHz	300MHz-1GHz	9kHz-30MHz	30MHz-300MHz	300MHz-1GHz	1GHz-18GHz	18GHz-40GHz
No.1 semi-anechoic chamber (±)	3.7dB	3.1dB	4.7dB	4.4dB	3.2dB	3.7dB	3.9dB	5.9dB	6.1dB
No.2 semi-anechoic chamber (±)	3.7dB	-	-	-	3.2dB	4.3dB	3.9dB	5.9dB	6.1dB
No.3 semi-anechoic chamber (±)	3.7dB	-	-	-	3.2dB	4.2dB	4.4dB	5.9dB	6.1dB
No.4 semi-anechoic chamber (±)	3.7dB	-	-	-	3.2dB	4.2dB	4.4dB	5.9dB	6.1dB

*10m/3m = Measurement distance

Conducted emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test(3m)

The data listed in this test report has enough margin, more than the site margin.

Other test except Conducted Emission and Spurious Emission (Radiated)

The measurement uncertainty for this test is 3.0dB.

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3.5 Test Location

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	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test set up, Test instruments and Data of EMI

Refer to APPENDIX 1 to 3.

SECTION 4: Operation of E.U.T. during testing

4.1 Operating Mode(s)

Test Item	Operating Mode	Tested frequency
Conducted emission Spurious Emission	IEEE802.11b Transmitting (Tx), 11Mbps *1)	2412MHz(L)
	IEEE802.11g Transmitting (Tx), 36Mbps *1)	2437MHz(M) 2462MHz(H)
	----- IEEE802.11b/g Receiving (Rx)	2437MHz(M)
6dB Bandwidth Maximum Peak Output Power Power Density 99% Occupied Bandwidth	IEEE802.11b Transmitting (Tx), 11Mbps *1)	2412MHz(L)
	IEEE802.11g Transmitting (Tx), 36Mbps *1)	2437MHz(M) 2462MHz(H)
Band Edge Compliance	IEEE802.11b Transmitting (Tx), 11Mbps *1)	2412MHz(L)
	IEEE802.11g Transmitting (Tx), 36Mbps *1)	2462MHz(H)
*1) The transmitting data shall be scrambled with the scramblers in accordance with IEEE Std and it was transmitted continuously.		

*As a result of preliminary test, the formal test was performed with the above modes, which had the maximum rated power.

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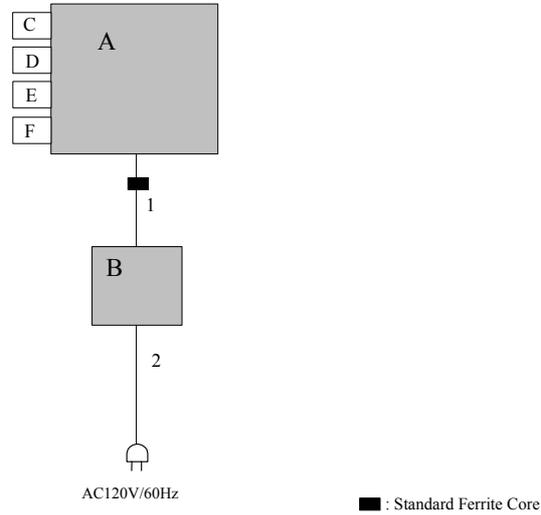
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4.2 Configuration and peripherals



* Cabling and setup(s) were taken into consideration and test data was taken under worse case conditions.
 * Since there was no difference of the noise at the pre-check of between the use of digital camera with USB cable and the use of USB memory (direct connection), the test was performed with the direct USB connection as typical usage of the product without connecting I/O cable.

Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Digital Photo Frame	VGF-CP1	1000009	Sony	EUT
B	AC Adapter	VGP-AC6V1	0812 A 00114	Sony	EUT
C	SD Memory Card 256MB	-	-	San Disk	-
D	Memory Stick 512MB	MSX-M512S	H413K1A	Sony	-
E	Compact Flash 64MB	SDCFB-64-J60	-	San Disk	-
F	USB Memory 512MB	AX0606T4B	-	San Disk	-

List of cables used

No.	Name	Length (m)	Shield	
			Cable	Connector
1	DC Cable	1.8	Unshielded	Unshielded
2	AC Cable	0.7	Unshielded	Unshielded

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SECTION 5: Conducted Emission

Test Procedure and conditions

EUT was placed on a urethane platform of nominal size, 1.0m by 0.5m, raised 80cm above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT, including peripherals aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from a Line Impedance Stabilization Network (LISN)/ Artificial mains Network (AMN) and excess AC cable was bundled in center.

For the tests on EUT with other peripherals (as a whole system)

I/O cable and AC cables that were connected to the peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. All unused 50ohm connectors of the LISN(AMN) were resistivity terminated in 50ohm when not connected to the measuring equipment.

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT in a Semi Anechoic Chamber or a Measurement Room.

The EUT was connected to a LISN (AMN).

An overview sweep with peak detection has been performed.

Detector : quasi-peak and average detector (IF BW 9 kHz)
Measurement range : 0.15-30MHz
Test data : APPENDIX 2
Test result : Pass

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SECTION 6: Spurious Emission

[Conducted]

Test Procedure

The Out of Band Emission was measured with a spectrum analyzer connected to the antenna port. It was measured based on "1. RF antenna conducted test" of "Guidance on Measurement of Digital Transmission Systems Operating under Section 15.247".

The following spectrum analyzer setting was used:

- RBW: 100kHz
- VBW: 300kHz
- Sweep: Auto
- Detector: Peak
- Trace: Max Hold

Test data : APPENDIX 2

Test result : Pass

[Radiated]

Test Procedure

It was measured based on "2. Radiated emission test" of "Guidance on Measurement of Digital Transmission Systems Operating under Section 15.247".

EUT was placed on a urethane platform of nominal size, 1.0m by 0.5m, raised 80cm above the conducting ground plane.

The Radiated Electric Field Strength intensity has been measured in a Semi Anechoic Chamber with a ground plane and at a distance of 3m (Below 10GHz) and 1m (Upper 10GHz).

The height of the measuring varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer (in linear mode).

The test was made with the detector (RBW/VBW) in the following table.

When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

In any 100kHz bandwidth outside the frequency band in which the spread spectrum intentional radiator is operating, the radio frequency power that is produced by the intentional radiator confirmed 20dB below that in the 100kHz bandwidth within the band that contains the highest level of the desired power, based on a radiated measurement.

20dBc was applied to the frequency over the limit of FCC 15.209 / Table 2 of RSS-210 2.7 (IC) and outside the restricted band of FCC 15.205 / Table 1 of RSS-210 2.7 (IC).

Frequency	Below 1GHz	Above 1GHz
Instrument used	Test Receiver / Spectrum Analyzer	Spectrum Analyzer
Detector	QP: BW 120kHz(T/R)	PK: RBW:1MHz/VBW: 1MHz
IF Bandwidth	20dBc : RBW: 100kHz VBW: 300kHz (S/A)	AV: RBW:1MHz/VBW:10Hz 20dBc : RBW:100kHz/VBW:300kHz

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

Test data : APPENDIX 2

Test result : Pass

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SECTION 7: Bandwidth

Test Procedure

The bandwidth was measured with a spectrum analyzer connected to the antenna port.
It was measured based on "Guidance on Measurement of Digital Transmission Systems Operating under Section15.247 ".
The following spectrum analyzer setting was used:

- Span: 50MHz
- RBW: 100kHz
- VBW: 300kHz
- Sweep: Auto
- Detector: Peak
- Trace: Max Hold

Test data : APPENDIX 2
Test result : Pass

SECTION 8: Maximum Peak Output Power

Test Procedure

The Maximum Peak Output Power was measured with a power meter (tested bandwidth: 50MHz) connected to the antenna port.
It was measured based on "Power Output Option 1" of "Guidance on Measurement of Digital Transmission Systems Operating under Section15.247 ".

Test data : APPENDIX 2
Test result : Pass

SECTION 9: Peak Power Density

[Conducted]

Test Procedure

The Peak Power Density was measured with a spectrum analyzer connected to the antenna port.
It was measured based on "PSD Option 1" of "Guidance on Measurement of Digital Transmission Systems Operating under Section15.247 ".

Test data : APPENDIX 2
Test result : Pass

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